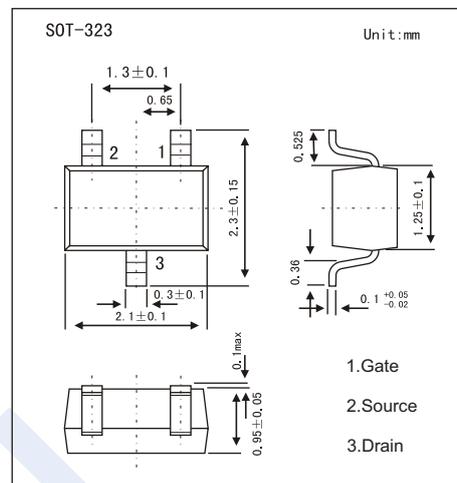
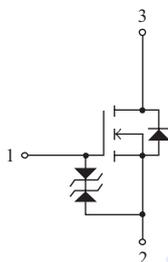


## N-Channel MOSFET

## MCH3476

## ■ Features

- $V_{DS} (V) = 20V$
- $I_D = 2.0 A$
- $R_{DS(ON)} < 125m\Omega$  ( $V_{GS} = 4.5V$ )
- $R_{DS(ON)} < 190m\Omega$  ( $V_{GS} = 2.5V$ )
- $R_{DS(ON)} < 310m\Omega$  ( $V_{GS} = 1.8V$ )
- 1.8V Drive
- ESD Diode-Protected Gate

■ Absolute Maximum Ratings  $T_a = 25^\circ C$ 

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	
Continuous Drain Current	$I_D$	2	A
Pulsed Drain Current $PW \leq 10\mu s$ , duty cycle $\leq 1\%$	$I_{DP}$	8	
Power Dissipation <sup>*1</sup>	$P_D$	0.8	W
Thermal Resistance.Junction- to-Ambient <sup>*1</sup>	$R_{thJA}$	156.2	$^\circ C/W$
Junction Temperature	$T_J$	150	$^\circ C$
Storage Temperature Range	$T_{stg}$	-55 to 150	

\*1: When mounted on ceramic substrate ( $900mm^2 \times 0.8mm$ )

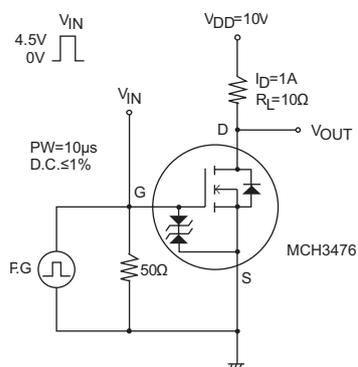
## N-Channel MOSFET

## MCH3476

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V <sub>DSS</sub>	I <sub>D</sub> =1mA, V <sub>GS</sub> =0V	20			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V			1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> =0V, V <sub>GS</sub> =±8V			±10	
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =10V, I <sub>D</sub> =1mA	0.4		1.3	V
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =1A			125	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =0.5A			190	
		V <sub>GS</sub> =1.8V, I <sub>D</sub> =0.3A			310	
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =10V, I <sub>D</sub> =1A		1.9		S
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =10V, f=1MHz		128		pF
Output Capacitance	C <sub>oss</sub>			28		
Reverse Transfer Capacitance	C <sub>rss</sub>			21		
Total Gate Charge	Q <sub>g</sub>			1.8		
Gate Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =10V, I <sub>D</sub> =2A		0.3		
Gate Drain Charge	Q <sub>gd</sub>			0.55		
Turn-On DelayTime	t <sub>d(on)</sub>	See specified Test Circuit		5.1		ns
Turn-On Rise Time	t <sub>r</sub>			11		
Turn-Off DelayTime	t <sub>d(off)</sub>			14.5		
Turn-Off Fall Time	t <sub>f</sub>			12		
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> =2A, V <sub>GS</sub> =0V			1.2	V

## ■ Switching Time Test Circuit



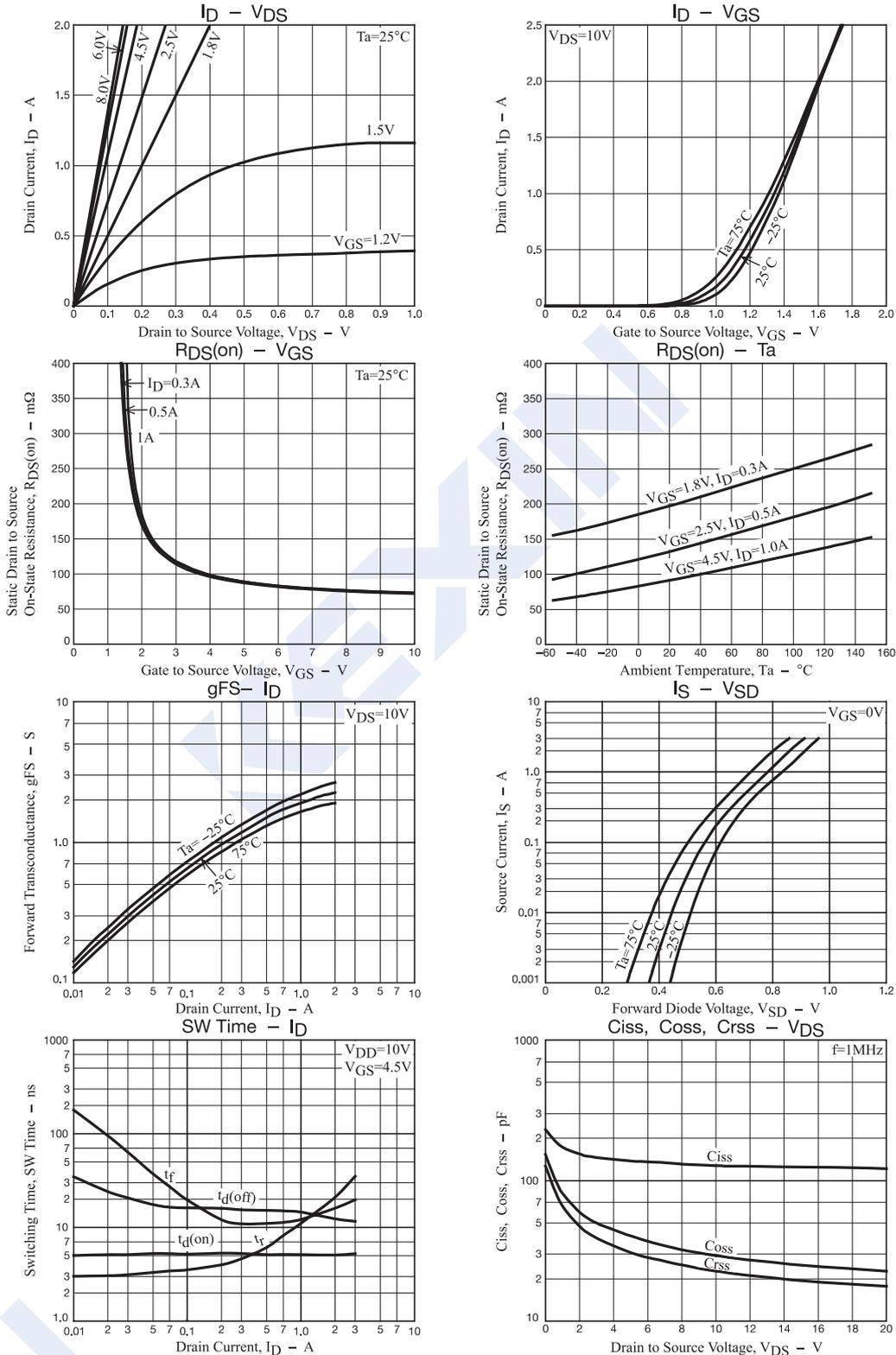
## ■ Marking

Marking	FH
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# N-Channel MOSFET

## MCH3476

■ Typical Characteristics



# N-Channel MOSFET

## MCH3476

